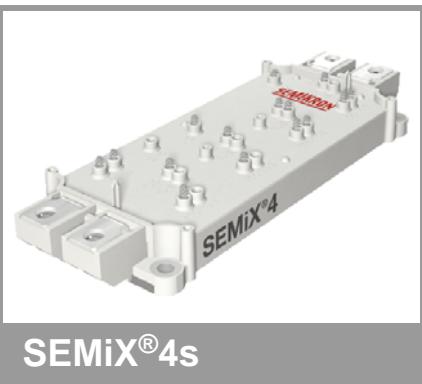


# SEMiX904GB126HDs



## Trench IGBT Modules

### SEMiX904GB126HDs

#### Preliminary Data

#### Features

- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$  with positive temperature coefficient
- High short circuit capability
- UL recognised file no. E63532

#### Typical Applications

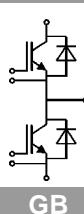
- AC inverter drives
- UPS
- Electronic Welding

#### Remarks

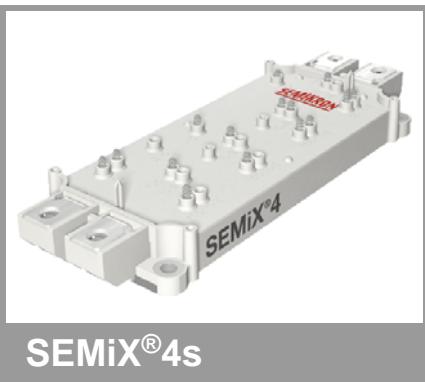
- Case temperatur limited to  $T_C=125^\circ\text{C}$  max.
- Not for new design

Absolute Maximum Ratings		Values		Unit
Symbol	Conditions			
<b>IGBT</b>				
$V_{CES}$		1200		V
$I_C$	$T_j = 150^\circ\text{C}$	$T_c = 25^\circ\text{C}$	821	A
		$T_c = 80^\circ\text{C}$	572	A
$I_{CRM}$	$I_{CRM} = 2 \times I_{Cnom}$		1200	A
$V_{GES}$		-20 ... 20		V
$t_{psc}$	$V_{CC} = 600\text{V}$ $V_{GE} \leq 20\text{V}$ $T_j = 125^\circ\text{C}$ $V_{CES} \leq 1200\text{V}$		10	$\mu\text{s}$
$T_j$		-40 ... 150		$^\circ\text{C}$
<b>Inverse diode</b>				
$I_F$	$T_j = 150^\circ\text{C}$	$T_c = 25^\circ\text{C}$	752	A
		$T_c = 80^\circ\text{C}$	516	A
$I_{FRM}$	$I_{FRM} = 2 \times I_{Fnom}$		1200	A
$I_{FSM}$	$t_p = 10\text{ms}$ , half sine wave, $T_j = 25^\circ\text{C}$		3600	A
$T_j$		-40 ... 150		$^\circ\text{C}$
<b>Module</b>				
$I_t(\text{RMS})$			600	A
$T_{stg}$		-40 ... 125		$^\circ\text{C}$
$V_{isol}$	AC sinus 50Hz, $t = 60\text{s}$		4000	V

Symbol	Conditions	min.	typ.	max.	Unit
<b>IGBT</b>					
$V_{CE(sat)}$	$I_{Cnom} = 600\text{A}$ $V_{GE} = 15\text{V}$ chiplevel	$T_j = 25^\circ\text{C}$	1.7	2.1	V
		$T_j = 125^\circ\text{C}$	2.00	2.45	V
$V_{CEO}$		$T_j = 25^\circ\text{C}$	1	1.2	V
		$T_j = 125^\circ\text{C}$	0.9	1.1	V
$r_{CE}$	$V_{GE} = 15\text{V}$	$T_j = 25^\circ\text{C}$	1.2	1.5	$\text{m}\Omega$
		$T_j = 125^\circ\text{C}$	1.8	2.3	$\text{m}\Omega$
$V_{GE(th)}$	$V_{GE}=V_{CE}$ , $I_C = 24\text{mA}$	5	5.8	6.5	V
$I_{CES}$	$V_{GE} = 0\text{V}$ $V_{CE} = 1200\text{V}$	$T_j = 25^\circ\text{C}$	0.12	0.36	$\text{mA}$
		$T_j = 125^\circ\text{C}$			$\text{mA}$
$C_{ies}$		$f = 1\text{MHz}$	43.1		nF
$C_{oes}$	$V_{CE} = 25\text{V}$ $V_{GE} = 0\text{V}$	$f = 1\text{MHz}$	2.25		nF
$C_{res}$		$f = 1\text{MHz}$	1.95		nF
$Q_G$	$V_{GE} = -8\text{V} \dots +15\text{V}$		4800		nC
$R_{Gint}$	$T_j = 25^\circ\text{C}$		1.25		$\Omega$
$t_{d(on)}$	$V_{CC} = 600\text{V}$		440		ns
$t_r$	$I_{Cnom} = 600\text{A}$		85		ns
$E_{on}$	$T_j = 125^\circ\text{C}$		60		mJ
$t_{d(off)}$	$R_{G\text{ on}} = 1.6\Omega$ $R_{G\text{ off}} = 1.6\Omega$		710		ns
$t_f$			130		ns
$E_{off}$			88		mJ
$R_{th(j-c)}$	per IGBT			0.05	K/W



# SEMiX904GB126HDs



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### SEMiX904GB126HDs

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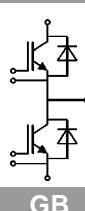
#### Typical Applications

- AC inverter drives
- UPS
- Electronic Welding

#### Remarks

- Case temperatur limited to  $T_C=125^\circ C$  max.
- Not for new design

Characteristics		Symbol	Conditions	min.	typ.	max.	Unit						
Inverse diode													
$V_F = V_{EC}$													
$I_{Fnom} = 600A$	$T_j = 25^\circ C$		$V_{GE} = 0V$ chiplevel	1.6	1.8	1.8	V						
	$T_j = 125^\circ C$												
$V_{FO}$	$T_j = 25^\circ C$			0.9	1	1.1	V						
	$T_j = 125^\circ C$			0.7	0.8	0.9	V						
$r_F$	$T_j = 25^\circ C$			0.8	1.0	1.2	$m\Omega$						
	$T_j = 125^\circ C$			1.2	1.3	1.5	$m\Omega$						
$I_{RRM}$	$I_{Fnom} = 600A$		$T_j = 125^\circ C$	625			A						
$Q_{rr}$	$di/dt_{off} = 8400A/\mu s$		$T_j = 125^\circ C$	165			$\mu C$						
$E_{rr}$	$V_{GE} = -15V$		$T_j = 125^\circ C$	75			$mJ$						
$R_{th(j-c)D}$	per diode			0.081			K/W						
Module													
$L_{CE}$				22			nH						
$R_{CC'+EE'}$	res., terminal-chip		$T_C = 25^\circ C$	0.7			$m\Omega$						
			$T_C = 125^\circ C$	1			$m\Omega$						
$R_{th(c-s)}$	per module			0.03			K/W						
$M_s$	to heat sink (M5)			3	5	5	Nm						
$M_t$	to terminals (M6)			2.5	5	5	Nm						
w				400			g						
Temperature sensor													
$R_{100}$	$T_c=100^\circ C$ ( $R_{25}=5 k\Omega$ )			0,493 $\pm 5\%$			$k\Omega$						
$B_{100/125}$	$R_{(T)}=R_{100}\exp[B_{100/125}(1/T-1/T_{100})];$ $T[K];$			3550 $\pm 2\%$			K						



# SEMiX904GB126HDs

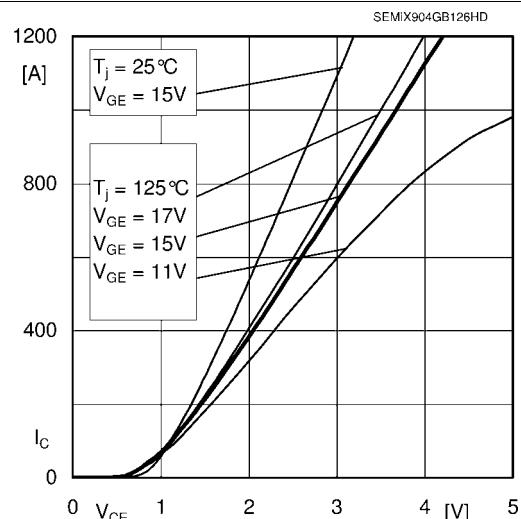


Fig. 1 Typ. output characteristic, inclusive  $R_{CC} + EE'$

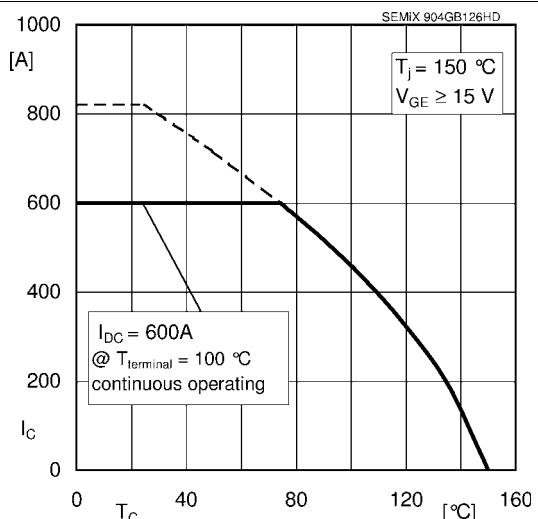


Fig. 2 Rated current vs. temperature  $I_C = f(T_C)$

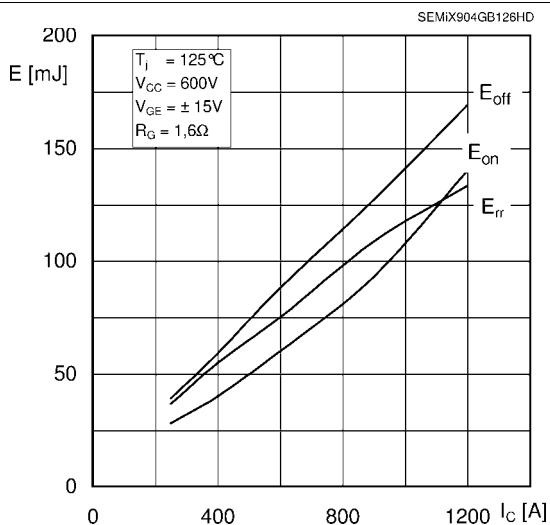


Fig. 3 Typ. turn-on /-off energy = f ( $I_C$ )

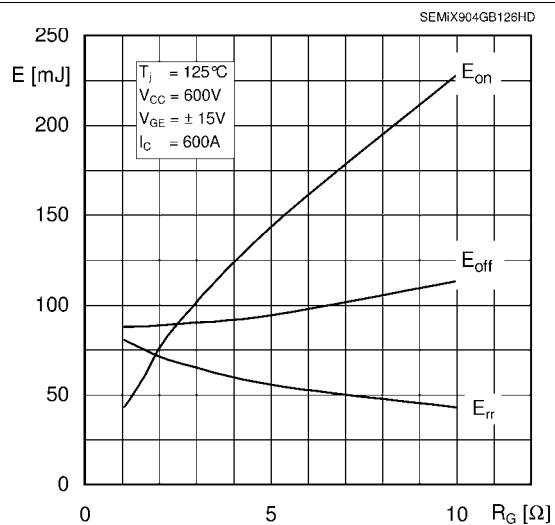


Fig. 4 Typ. turn-on /-off energy = f ( $R_G$ )

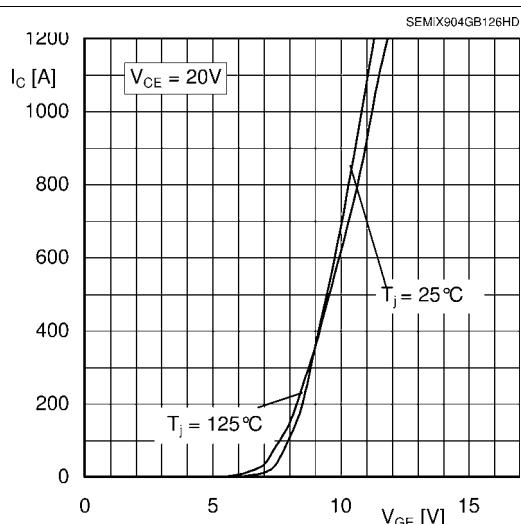


Fig. 5 Typ. transfer characteristic

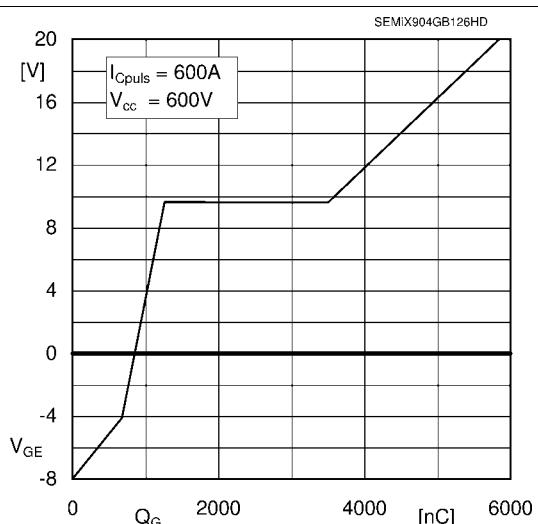


Fig. 6 Typ. gate charge characteristic

# SEMiX904GB126HDs

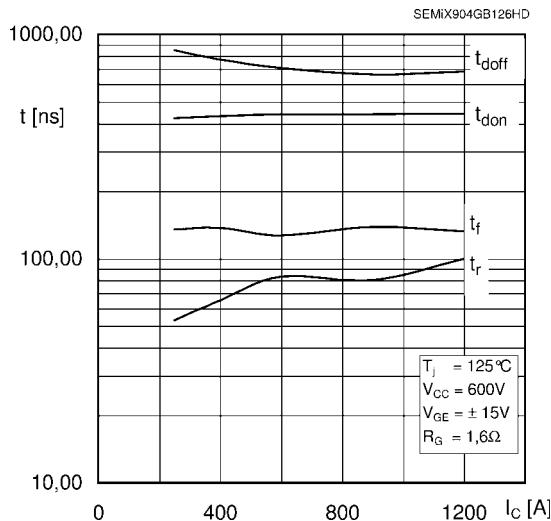


Fig. 7 Typ. switching times vs.  $I_C$

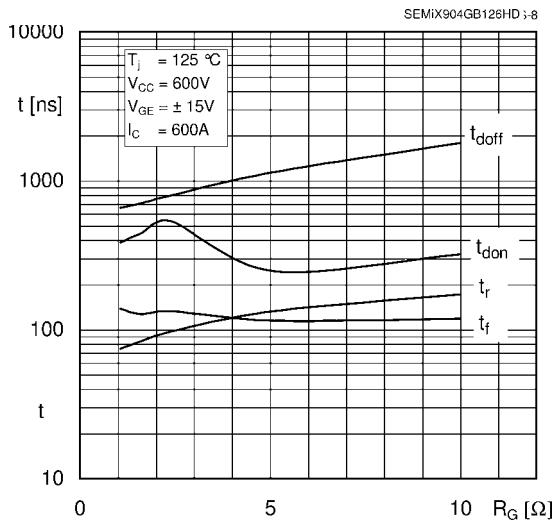


Fig. 8 Typ. switching times vs. gate resistor  $R_G$

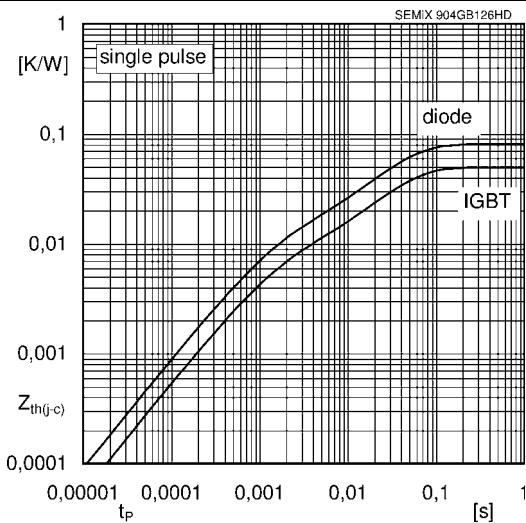


Fig. 9 Typ. transient thermal impedance

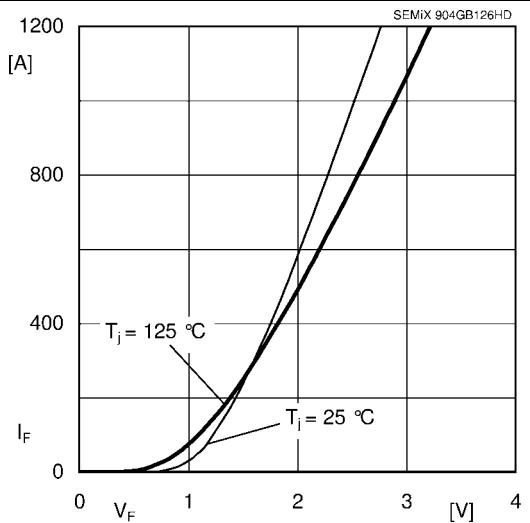


Fig. 10 Typ. CAL diode forward charact., incl.  $R_{CC+EE}$

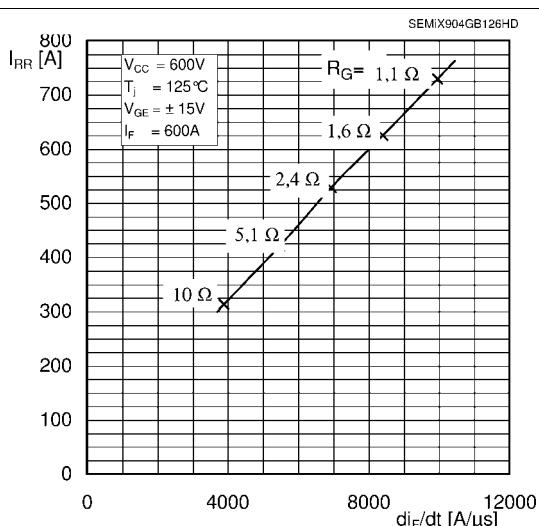


Fig. 11 Typ. CAL diode peak reverse recovery current

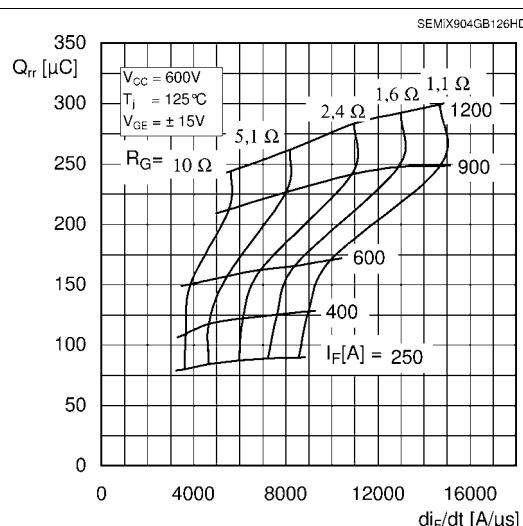
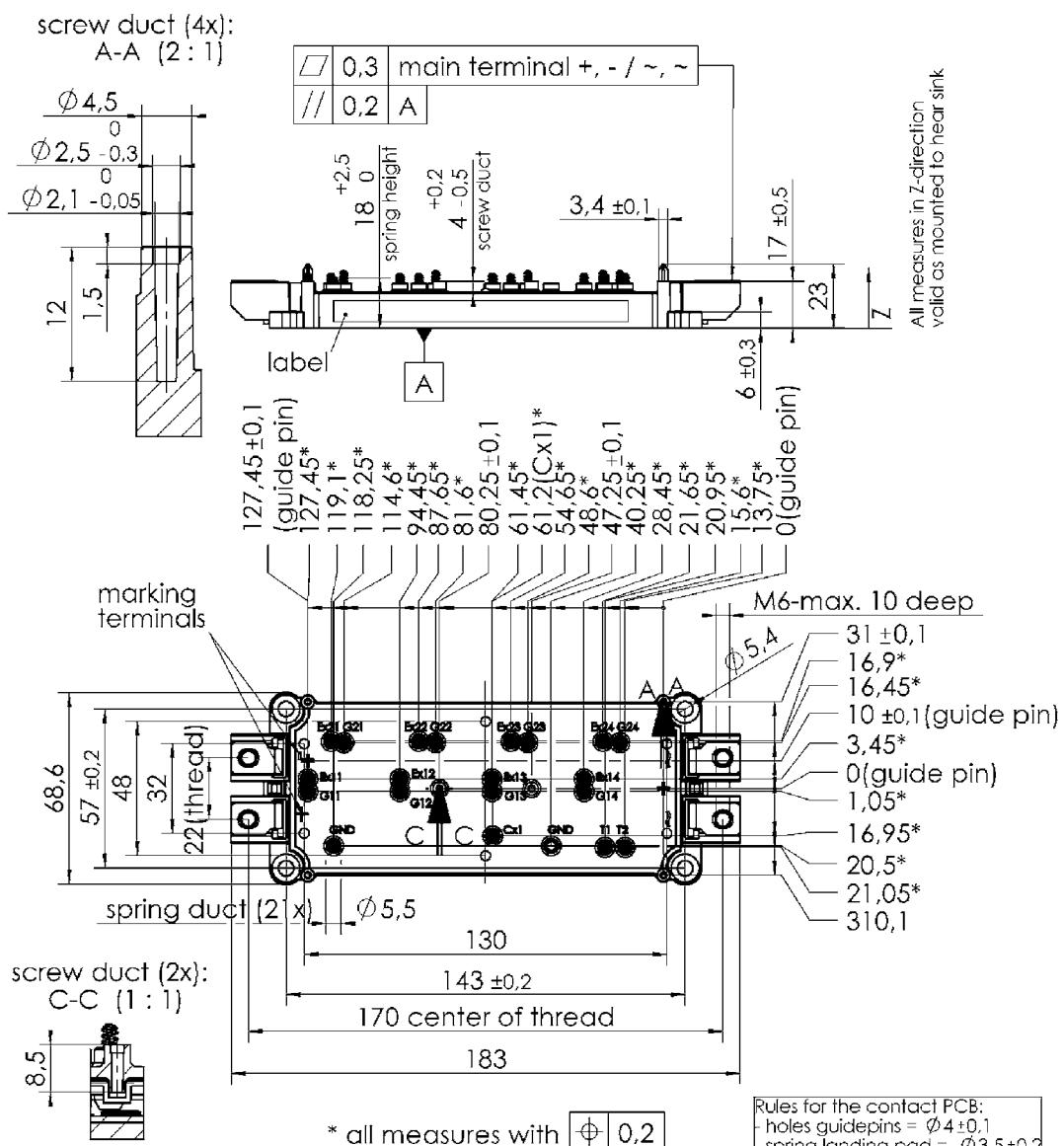


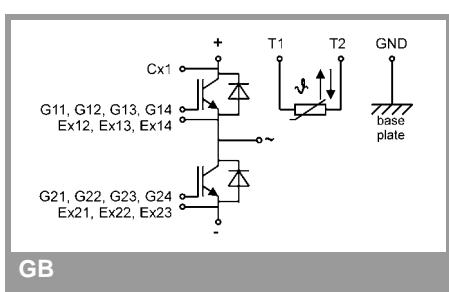
Fig. 12 Typ. CAL diode recovery charge

# SEMiX904GB126HDs

case: SEMiX 4s



SEMiX 4s



This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX

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